



RADIO TEST REPORT

Test Report No. : 11306371S-A-R1

Applicant : Sony Corporation
Type of Equipment : Digital Paper
Model No. : DPT-RP1
FCC ID : AK8DPTRP1
Test regulation : FCC Part 15 Subpart C: 2016
Test item : Antenna terminal conducted tests
Test Result : Complied

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2. The results in this report apply only to the sample tested.
3. This sample tested is in compliance with the above regulation.
4. The test results in this report are traceable to the national or international standards.
5. The opinions and the interpretations to the result of the description in this report are outside scopes where UL Japan has been accredited.
6. This test report covers Radio technical requirements. It does not cover administrative issues such as Manual or non-Radio test related Requirements. (if applicable)
7. This report is a revised version of 11306371S-A. 11306371S-A is replaced with this report.

Date of test:

July 2, 2016

Representative test engineer:



Hiroyuki Morikawa

Engineer

Consumer Technology Division

Approved by:



Toyokazu Imamura

Leader

Consumer Technology Division



JAB
Testing
RTL02610

- The testing in which "Non-accreditation" is displayed is outside the accreditation scopes in UL Japan.
 There is no testing item of "Non-accreditation".

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13-EM-F0429

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SECTION 1: Customer information

Company Name : Sony Corporation
Brand Name : SONY
Address : 1-7-1 Konan, Minato-ku, Tokyo 108-0075, Japan

SECTION 2: Equipment under test (E.U.T.)

2.1 Identification of E.U.T.

Type of Equipment : Digital Paper
Model No. : DPT-RP1
Serial No. : Refer to Section 4, Clause 4.2
Rating : DC 3.7 V
Receipt Date of Sample : May 30, 2016
Country of Mass-production : Japan
Condition of EUT : Production prototype
(Not for Sale: This sample is equivalent to mass-produced items.)
Modification of EUT : No Modification by the test lab.

2.2 Product Description

Model: DPT-RP1 (referred to as the EUT in this report) is a Digital Paper.

Clock frequency : 156 MHz (CPLD), 667 MHz (LPDDR3), 200 MHz (eMMC), 40 MHz (WLAN/BT)
208 MHz (WLAN/BT), 32.768 kHz (clock), 26 MHz (CPU), 27 MHz (NFC)

Radio Specification

Equipment name	IEEE 802.11 2x2 MIMO a/b/g/n/ac Wireless LAN + Bluetooth + NFC		
Frequency of operation	Bluetooth	2.4GHz band: 2402-2480 MHz (BDR (Basic Data Rate), EDR (Enhanced Data Rate), LE (Low Energy mode))	
	WLAN	2.4GHz band: 2412-2462 MHz (b.g.n(HT20)); W52 (U-NII-1): 5180-5240 MHz (a,n(HT20),ac(VHT20)) / 5190-5230 MHz (n(HT40),ac(VHT40)) / 5210 MHz (ac(VHT80)); W53 (U-NII-2A): 5260-5320 MHz (a,n(HT20),ac(VHT20)) / 5270-5310 MHz (n(HT40),ac(VHT40)) / 5290 MHz (ac(VHT80)); W56 (U-NII-2C): 5500-5720 MHz (a,n(HT20),ac(VHT20)) / 5510-5710 MHz (n(HT40),ac(VHT40)) / 5530-5690 MHz (ac(VHT80)) W58 (U-NII-3): 5745-5825 MHz (a,n(HT20),ac(VHT20)) / 5755-5795 MHz (n(HT40),ac(VHT40)) / 5775 MHz (ac(VHT80))	
	NFC	13.56 MHz	
Operation mode	Wi-Fi	Bluetooth	NFC
Channel spacing	5 MHz (2.4 GHz band), 20 MHz (W52, W53, W56, W58)	1 MHz (BDR, EDR), 2 MHz (LE)	-
Bandwidth	20 MHz (b.g.a,n(HT20),ac(VHT20)), 40 MHz (n(HT40),ac(VHT40)), 80 MHz (ac(VHT80))	79 MHz	-
Type of modulation	DSSS: DBPSK, DQPSK, CCK OFDM: BPSK, QPSK, 16QAM, 64QAM, 256QAM(*1) (*1. 256QAM is only supported by 11ac mode.)	FHSS: GFSK (*. EDR: GFSK+ $\pi/4$ -DQPSK, GFSK+ 8DPSK)	ASK
Antenna	antenna #A (Wi-Fi)	antenna #B (Wi-Fi+Bluetooth)	
Antenna type	Loop		
Antenna gain (Peak)	3.75 dBi (2.4 GHz), 2.81 dBi (5 GHz) (*.including cable loss)	1.38 dBi (2.4 GHz), 4.29 dBi (5 GHz) (*.including cable loss)	
Antenna	NFC antenna		
Antenna type	Loop		
Card type	type A, type F		

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SECTION 3: Test specification, procedures & results

3.1 Test Specification

Test Specification : FCC Part 15 Subpart C
FCC part 15 final revised on April 6, 2016.
Title : FCC 47CFR Part15 Radio Frequency Device Subpart C Intentional Radiators
Section 15.207 Conducted limits
Section 15.247 Operation within the bands 902-928MHz,
2400-2483.5MHz, and 5725-5850MHz

The EUT has been tested for compliance with FCC Part 15 Subpart B. Refer to the test report 11306371S-F.

3.2 Procedures and results

Item	Test Procedure	Specification	Worst Margin	Results	Remarks
Conducted Emission	FCC: ANSI C63.10-2013 6. Standard test methods IC: RSS-Gen 8.8	FCC: Section 15.207 IC: RSS-Gen 8.8	-	-	*1)
Carrier Frequency Separation	FCC: FCC Public Notice DA 00-705 IC: -	FCC: Section15.247(a)(1) IC: RSS-247 5.1 (2)	See data.	Complied	Conducted
20dB Bandwidth	FCC: FCC Public Notice DA 00-705 IC: -	FCC: Section15.247(a)(1) IC: RSS-247 5.1 (1)		-	Conducted
Number of Hopping Frequency	FCC: FCC Public Notice DA 00-705 IC: -	FCC: Section15.247(a)(1)(iii) IC: RSS-247 5.1 (4)		Complied	Conducted
Dwell time	FCC: FCC Public Notice DA 00-705 IC: -	FCC: Section15.247(a)(1)(iii) IC: RSS-247 5.1 (4)		Complied	Conducted
Maximum Peak Output Power	FCC: FCC Public Notice DA 00-705 IC: RSS-Gen 6.12	FCC: Section15.247(a)(b)(1) IC: RSS-247 5.4 (2)		Complied	Conducted
Spurious Emission & Band Edge Compliance	FCC: FCC Public Notice DA 00-705 IC: RSS-Gen 6.13	FCC: Section15.247(d) IC: RSS-247 5.5 RSS-Gen 8.9 RSS-Gen 8.10	-	Complied	Conducted *2)

Note: UL Japan, Inc.'s EMI Work Procedures No. 13-EM-W0420 and 13-EM-W0422.

*1) Refer to the test report: 11306372M-A.

*2) Refer to the test report: 11306372M-A for Radiated emission (above 30 MHz).

* In case any questions arise about test procedure, ANSI C63.10: 2013 is also referred.

FCC Part 15.31 (e)

This EUT provides stable voltage (DC 3.3 V and 1.8 V) constantly to RF transmitter regardless of input voltage. Therefore, this EUT complies with the requirement.

FCC Part 15.203 Antenna requirement

It is impossible for end users to replace the antenna, because the antenna is mounted inside of the EUT. Therefore, the equipment complies with the requirement.

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3.3 Addition to standard

Item	Test Procedure	Specification	Worst margin	Results	Remarks
99% Occupied Bandwidth	IC: RSS-Gen 6.6	IC: -	N/A	-	Conducted

Other than above, no addition, exclusion nor deviation has been made from the standard.

3.4 Uncertainty

The following uncertainties have been calculated to provide a confidence level of 95 % using a coverage factor $k = 2$.
Shonan EMC Lab.

Antenna terminal test	Uncertainty (+/-)
Power Measurement above 1 GHz (Average Detector)_SPM-06	0.76 dB
Power Measurement above 1 GHz (Peak Detector)_SPM-06	0.79 dB
Power Measurement above 1 GHz (Average Detector)_SPM-07	0.74 dB
Power Measurement above 1 GHz (Peak Detector)_SPM-07	1.08 dB
Spurious emission (Conducted) below 1GHz	1.5 dB
Spurious emission (Conducted) 1 GHz-3 GHz	1.7 dB
Spurious emission (Conducted) 3 GHz-18 GHz	2.4 dB
Spurious emission (Conducted) 18 GHz-26.5 GHz	2.5 dB
Spurious emission (Conducted) 26.5 GHz-40 GHz	2.5 dB
Bandwidth Measurement	0.66 %
Duty cycle and Time Measurement	0.012 %

3.5 Test Location

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Telephone: +81 463 50 6400, Facsimile: +81 463 50 6401
JAB Accreditation No. RTL02610

Test site	IC Registration Number	Width x Depth x Height (m)	Size of reference ground plane (m) / horizontal conducting plane	Maximum measurement distance
No.1 Semi-anechoic chamber	2973D-1	20.6 x 11.3 x 7.65	20.6 x 11.3	10m
No.2 Semi-anechoic chamber	2973D-2	20.6 x 11.3 x 7.65	20.6 x 11.3	10m
No.3 Semi-anechoic chamber	2973D-3	12.7 x 7.7 x 5.35	12.7 x 7.7	5m
No.4 Semi-anechoic chamber	-	8.1 x 5.1 x 3.55	8.1 x 5.1	-
No.1 Shielded room	-	6.8 x 4.1 x 2.7	6.8 x 4.1	-
No.2 Shielded room	-	6.8 x 4.1 x 2.7	6.8 x 4.1	-
No.3 Shielded room	-	6.3 x 4.7 x 2.7	6.3 x 4.7	-
No.4 Shielded room	-	4.4 x 4.7 x 2.7	4.4 x 4.7	-
No.5 Shielded room	-	7.8 x 6.4 x 2.7	7.8 x 6.4	-
No.6 Shielded room	-	7.8 x 6.4 x 2.7	7.8 x 6.4	-
No.8 shielded room	-	3.45 x 5.5 x 2.4	3.45 x 5.5	-
No.1 Measurement room	-	2.55 x 4.1 x 2.5	-	-

3.6 Test data, Test instruments, and Test set up

Refer to APPENDIX.

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SECTION 4: Operation of E.U.T. during testing

4.1 Operating Mode(s)

Bluetooth (BT): Transmitting (Tx), Payload: PRBS9

Details of Operating Mode(s)

Test Item	Mode	Tested frequency
Spurious Emission (Conducted)	Tx (Hopping Off) DH5, 3DH5	2402 MHz 2441 MHz 2480 MHz
Carrier Frequency Separation	Tx (Hopping On) DH5, 3DH5	2402 MHz 2441 MHz 2480 MHz
20dB Bandwidth	Tx (Hopping Off) DH5, 3DH5	2402 MHz 2441 MHz 2480 MHz
Number of Hopping Frequency	Tx (Hopping On) DH5, 3DH5	-
Dwell time	Tx (Hopping On), -DH1, DH3, DH5 -3DH1, 3DH3, 3DH5	-
Maximum Peak Output Power	Tx (Hopping Off) DH5, 2DH5, 3DH5	2402 MHz 2441 MHz 2480 MHz
Band Edge Compliance (Conducted)	Tx DH5, 3DH5 -Hopping On -Hopping Off	2402 MHz 2480 MHz
99% Occupied Bandwidth	Tx DH5, 3DH5 -Hopping On -Hopping Off	2402 MHz 2441 MHz 2480 MHz
<p>*As a result of preliminary test, the formal test was performed with the above modes, which had the maximum payload length (except Dwell time test)</p> <p>*2DH mode (2Mb/s EDR: pi/4DQPSK) was excluded for other tests than power measurement by using 3DH mode (3 Mb/s EDR: 8DPSK) as a representative.</p> <p>* It is considered that the non-tested packet type (e.g. inquiry) can be omitted as it is complied with above all test items based on Bluetooth Core specification.</p> <p>*EUT has the power settings by the software as follows; Power settings: BDR: 2 dBm EDR: 2 dBm</p> <p>Software: DutApiMimoBtFmBridgeEth.exe Version 2.0.0.75</p> <p>*This setting of software is the worst case.</p> <p>Any conditions under the normal use do not exceed the condition of setting.</p> <p>In addition, end users cannot change the settings of the output power of the product.</p>		

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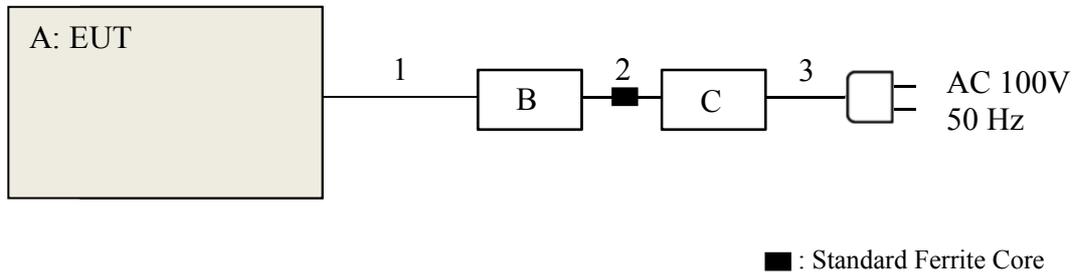
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4.2 Configuration and peripherals



Description of EUT and support equipment

No.	Item	Model number	Serial number	Manufacturer	Remarks
A	Digital Paper	DPT-RP1	9002565	Sony Corporation	EUT
B	Laptop PC	7666-77J	LV-B8PZ8 08/05	Lenovo	-
C	AC Adaptor	92P1213	11S92P1213Z1ZDDZ92C2B0	Lenovo	-

List of cables used

No.	Name	Length (m)	Shield		Remarks
			Cable	Connector	
1	USB	1.0	Shielded	Shielded	-
2	DC	1.8	Unshielded	Unshielded	-
3	AC	1.0	Unshielded	Unshielded	-

SECTION 5: Antenna Terminal Conducted Tests

Test Procedure

The tests were made with below setting connected to the antenna port.

Test	Span	RBW	VBW	Sweep time	Detector	Trace	Instrument used
20dB Bandwidth	3 MHz	30 kHz	100 kHz	Auto	Peak	Max Hold	Spectrum Analyzer
99% Occupied Bandwidth	Enough width to display emission skirts	1 to 5 % of OBW	Three times of RBW	Auto	Sample	Max Hold *1)	Spectrum Analyzer
Maximum Peak Output Power	-	-	-	Auto	Peak Average *3)	-	Power Meter (Sensor: 50MHz BW)
Carrier Frequency Separation	3 MHz	100 kHz	300 kHz	Auto	Peak	Max Hold	Spectrum Analyzer
Number of Hopping Frequency	30 MHz	300 kHz	1 MHz	Auto	Peak	Max Hold	Spectrum Analyzer
Dwell Time	Zero Span	100 kHz, 1 MHz	300 kHz, 3 MHz	As necessary capture the entire dwell time per hopping channel	Peak	Clear Write	Spectrum Analyzer
Conducted Spurious Emission *2)	9 kHz to 150 kHz	200 Hz	620 Hz	Auto	Peak	Max Hold	Spectrum Analyzer
	150 kHz to 30 MHz	10 kHz	27 kHz				
	30 MHz to 25 GHz	100 kHz	300 kHz				
Conducted Spurious Emission Band Edge compliance	10 MHz	100 kHz	300 kHz	Auto	Peak	Max Hold	Spectrum Analyzer

*1) The measurement was performed with Max Hold since the duty cycle was not 100 %.

*2) In the frequency range below 30MHz, RBW was narrowed to separate the noise contents.

Then, wide-band noise near the limit was checked separately, however the noise was not detected as shown in the chart.

(9 kHz -150 kHz: RBW = 200 Hz, 150 kHz - 30 MHz: RBW = 10 kHz) *3) Reference data

The test results and limit are rounded off to two decimals place, so some differences might be observed.

Test data : APPENDIX
Test result : Pass

APPENDIX 1: Test data

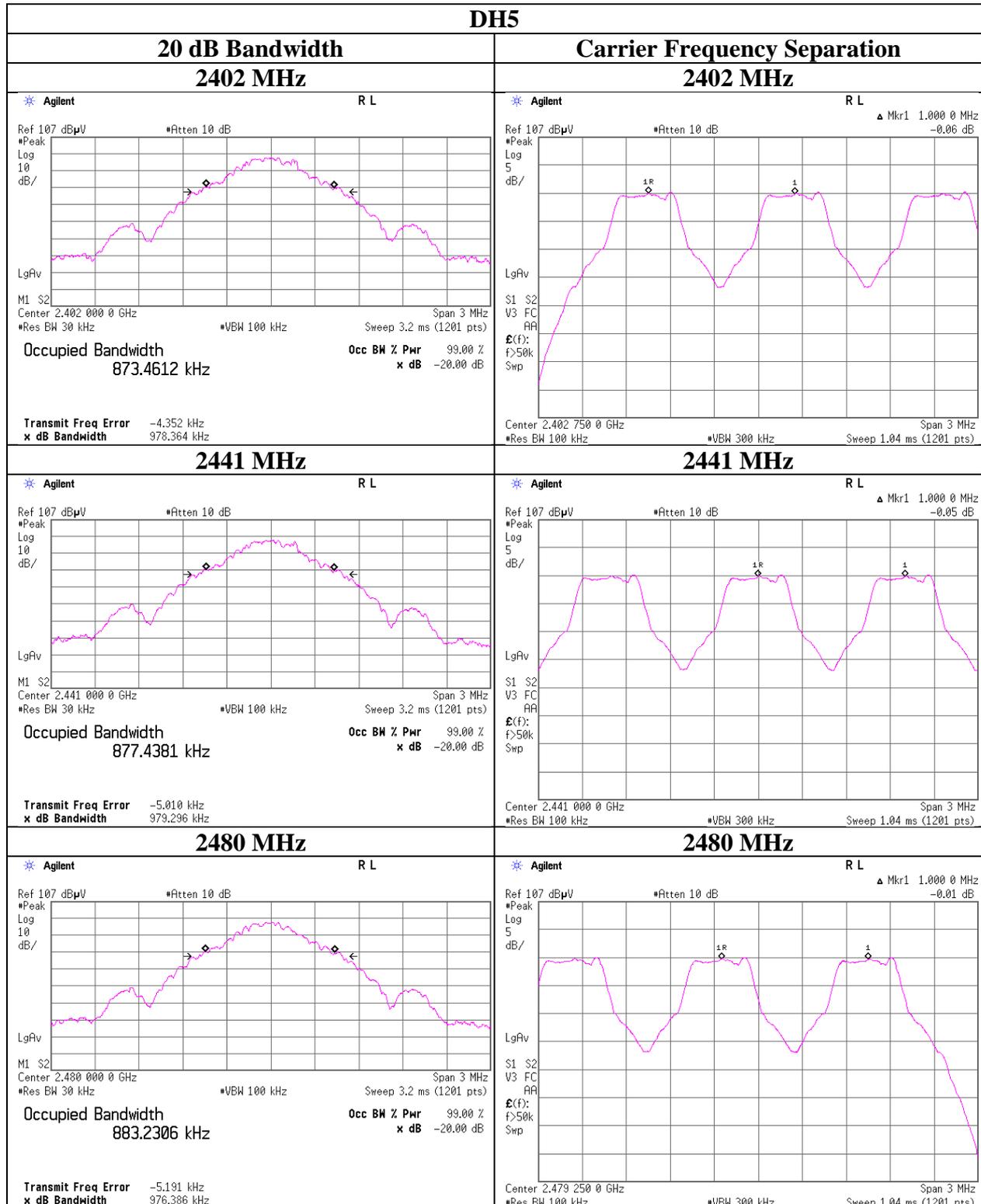
20dB Bandwidth and Carrier Frequency Separation

Test place Shonan EMC Lab. No.5 Shielded Room
Report No. 11306371S-A-R1
Date July 2, 2016
Temperature / Humidity 25 deg. C / 51 % RH
Engineer Hiroyuki Morikawa
Mode Tx, Hopping Off, DH5

Mode	Freq. [MHz]	20dB Bandwidth [MHz]	Carrier Frequency Separation [MHz]	Limit for Carrier Frequency separation [MHz]
DH5	2402.0	0.978	1.000	>= 0.652
DH5	2441.0	0.979	1.000	>= 0.653
DH5	2480.0	0.976	1.000	>= 0.651
3DH5	2402.0	1.300	1.000	>= 0.866
3DH5	2441.0	1.299	1.000	>= 0.866
3DH5	2480.0	1.299	1.000	>= 0.866

Limit: Two-thirds of 20dB Bandwidth or 25kHz (whichever is greater)
No limit applies to 20dB Bandwidth.

20dB Bandwidth and Carrier Frequency Separation



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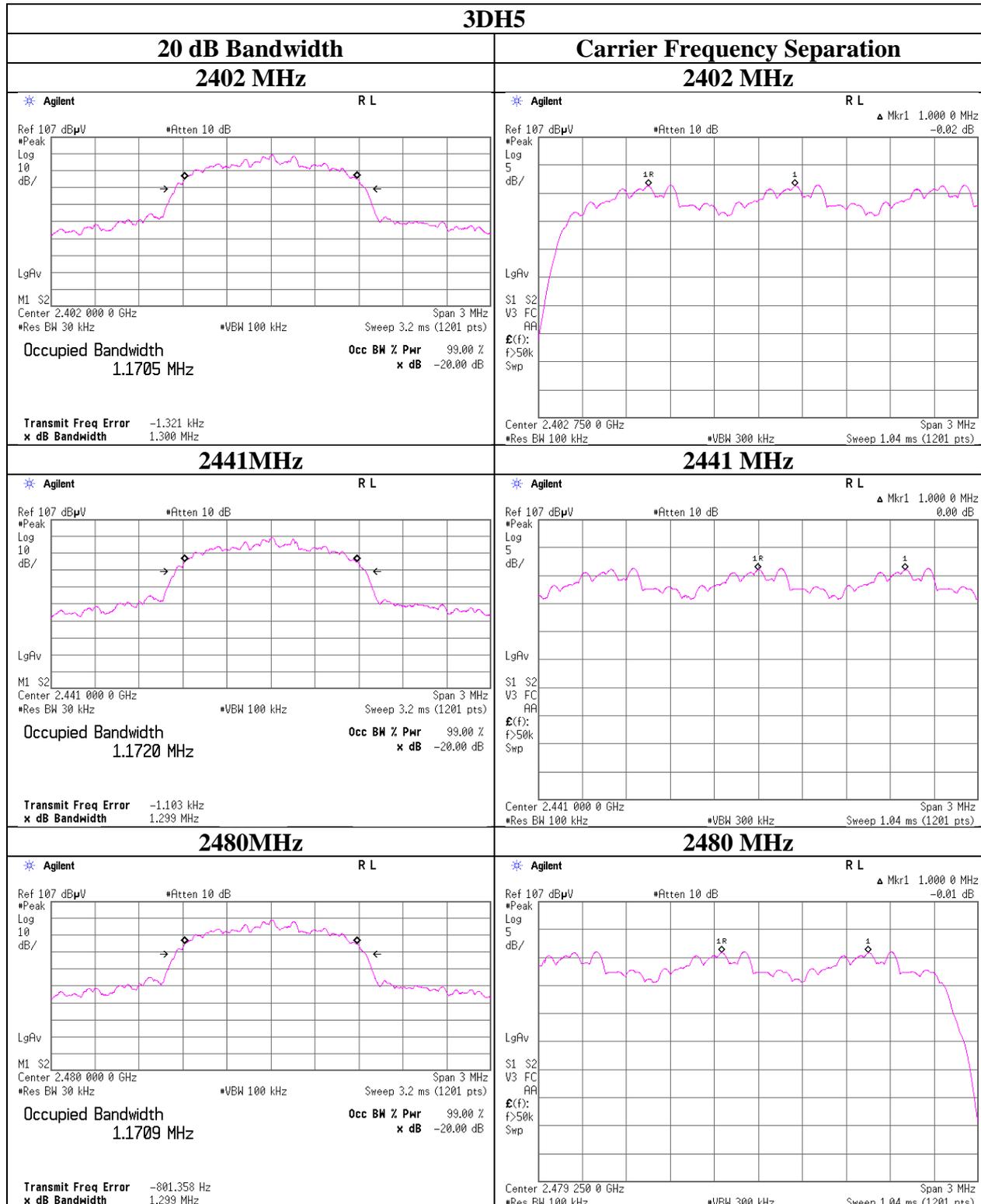
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20dB Bandwidth and Carrier Frequency Separation



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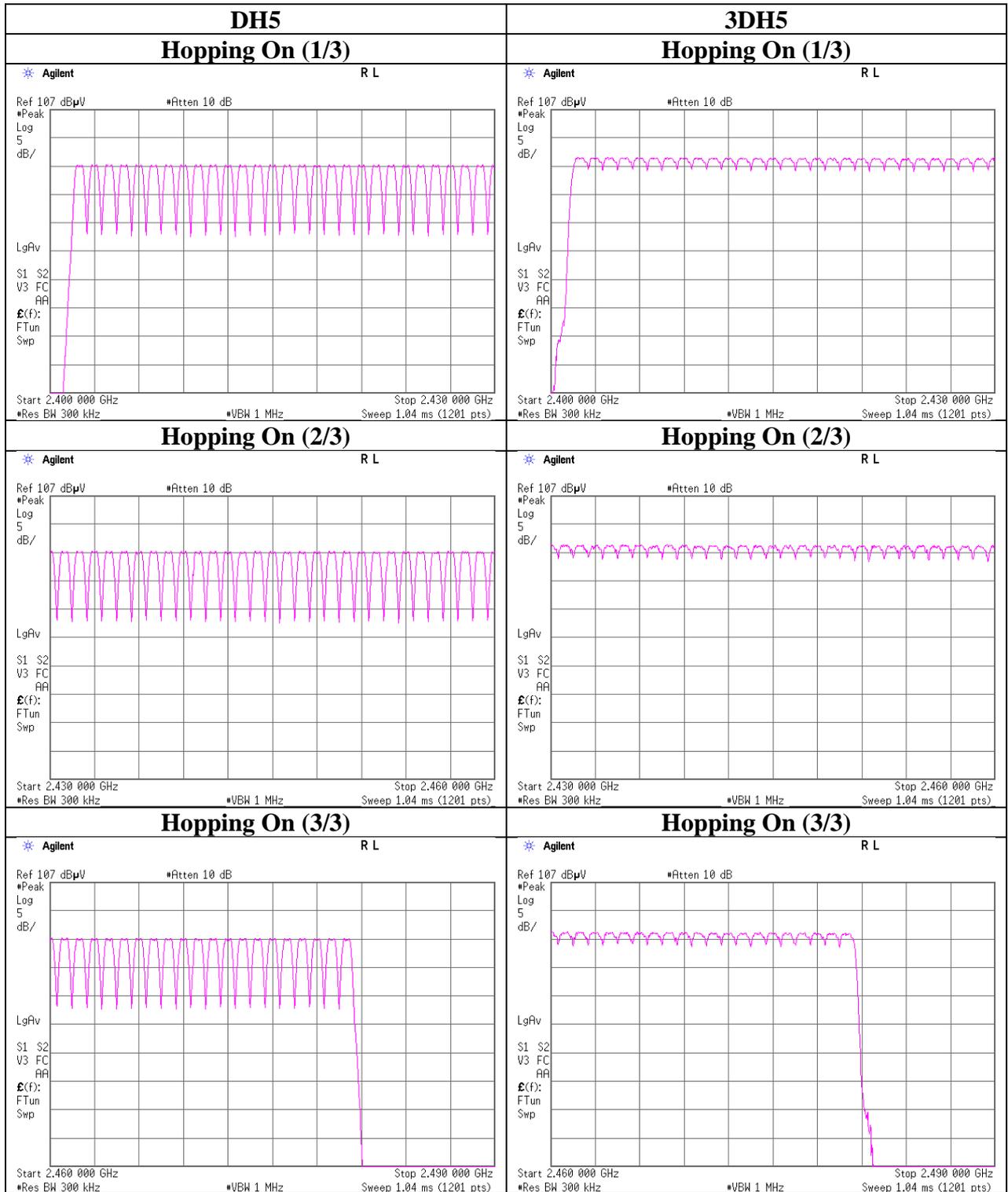
Number of Hopping Frequency

Test place Shonan EMC Lab. No.5 Shielded Room
Report No. 11306371S-A-R1
Date July 2, 2016
Temperature / Humidity 25 deg. C / 51 % RH
Engineer Hiroyuki Morikawa
Mode Tx, Hopping On

Mode	Number of channel [channels]	Limit [channels]
DH5	79	>= 15
3DH5	79	>= 15

Test was not performed at AFH mode whose number of hopping channel is 20 channels because this Bluetooth radio is in compliance of Bluetooth Specification.

Number of Hopping Frequency



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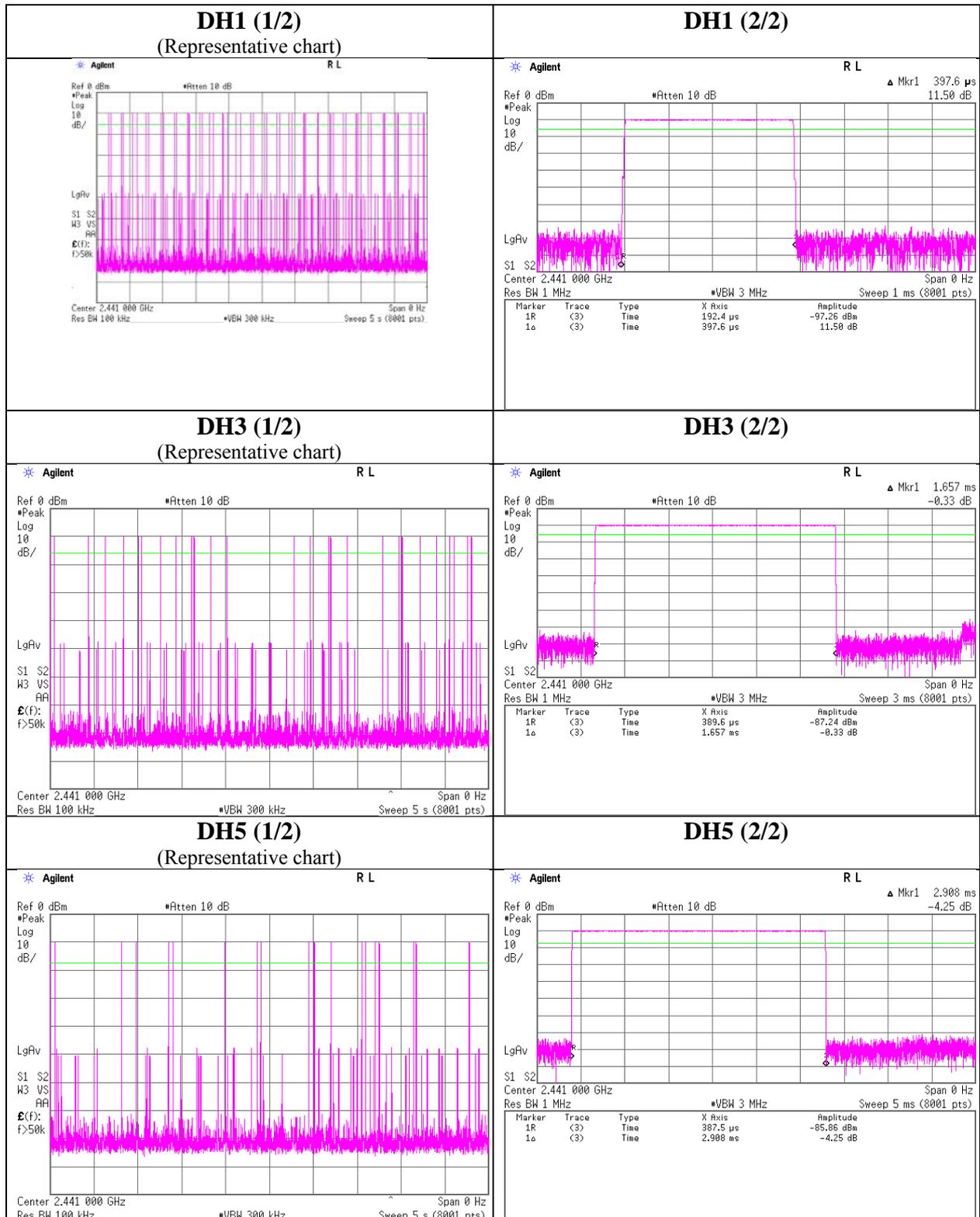
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Dwell time



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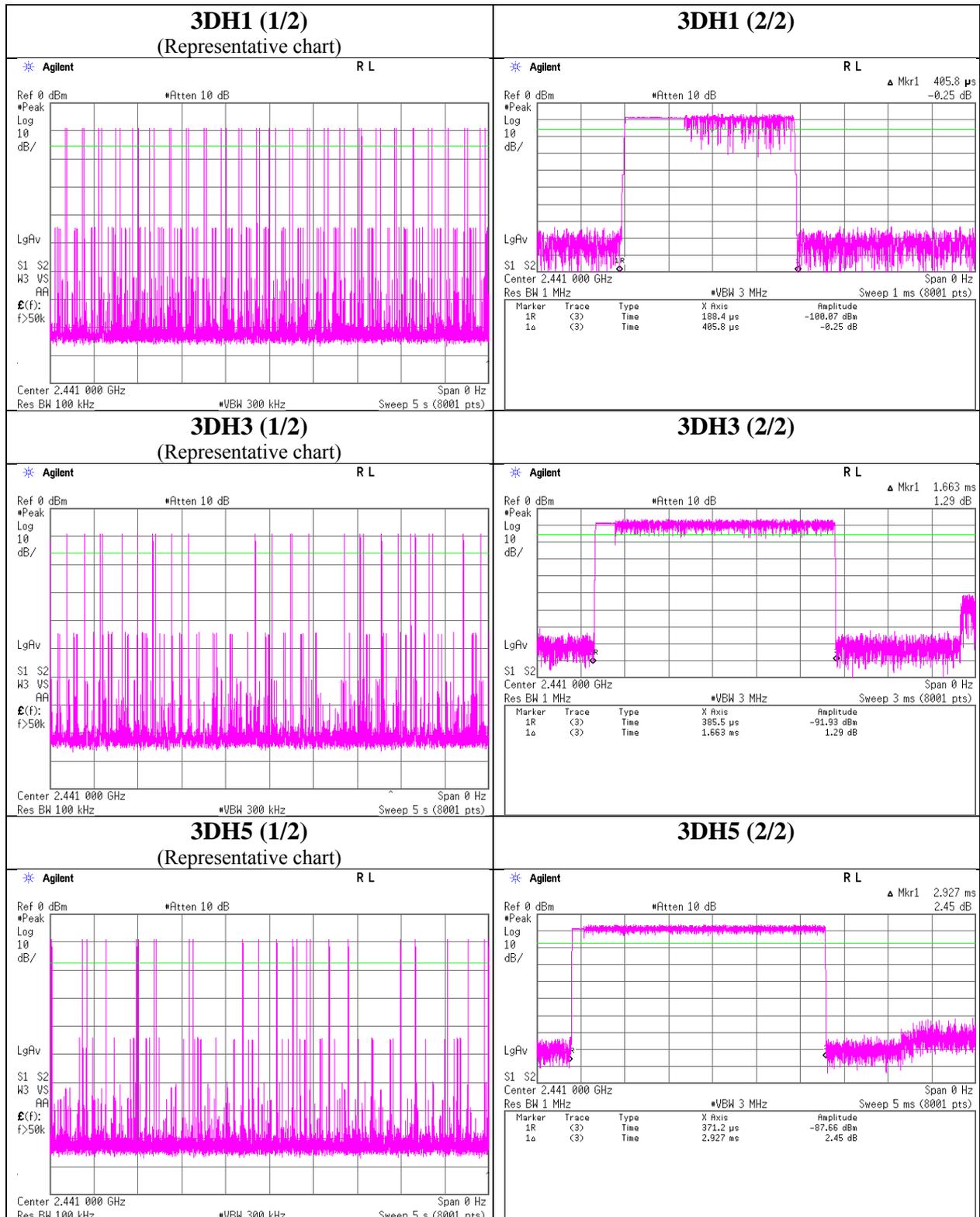
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Dwell time



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Maximum Peak Output Power

Test place : Shonan EMC Lab. No.5 Shielded Room
Report No. : 11306371S-A-R1
Date : July 2, 2016
Temperature / Humidity : 25 deg. C / 51 % RH
Engineer : Hiroyuki Morikawa
Mode : Tx, Hopping Off

Mode	Freq. [MHz]	Reading [dBm]	Cable Loss [dB]	Atten. Loss [dB]	Result		Limit		Margin [dB]
					[dBm]	[mW]	[dBm]	[mW]	
DH5	2402.0	-9.59	2.00	9.92	2.33	1.71	20.96	125	18.63
DH5	2441.0	-9.71	2.05	9.92	2.26	1.68	20.96	125	18.70
DH5	2480.0	-9.85	2.04	9.92	2.11	1.63	20.96	125	18.85
2DH5	2402.0	-6.15	2.00	9.92	5.77	3.78	20.96	125	15.19
2DH5	2441.0	-6.36	2.05	9.92	5.61	3.64	20.96	125	15.35
2DH5	2480.0	-6.56	2.04	9.92	5.40	3.47	20.96	125	15.56
3DH5	2402.0	-5.86	2.00	9.92	6.06	4.04	20.96	125	14.90
3DH5	2441.0	-6.04	2.05	9.92	5.93	3.92	20.96	125	15.03
3DH5	2480.0	-6.27	2.04	9.92	5.69	3.71	20.96	125	15.27

Sample Calculation:

Result = Reading + Cable Loss (including the cable(s) customer supplied) + Attenuator Loss

Test was not performed at AFH mode, because the decrease of number of channel (min: 20ch) at AFH mode does not influence on the output power and bandwidth of the EUT.

As this device had AFH mode and frequency separation could not meet the requirement of over 20dB BW without 2/3 relaxation, 125mW power limit was applied to it.

Average Output Power
(Reference data for SAR testing)

Test place Shonan EMC Lab. No.5 Shielded Room
Report No. 11306371S-A-R1
Date July 2, 2016
Temperature / Humidity 25 deg. C / 51 % RH
Engineer Hiroyuki Morikawa
Mode Tx, Hopping Off

Mode	Freq. [MHz]	Reading [dBm]	Cable Loss [dB]	Atten. Loss [dB]	Result (Time average)		Duty factor [dB]	Result (Burst power average)	
					[dBm]	[mW]		[dBm]	[mW]
DH5	2402.0	-11.11	2.00	9.92	0.81	1.21	1.11	1.92	1.56
DH5	2441.0	-11.18	2.05	9.92	0.79	1.20	1.11	1.90	1.55
DH5	2480.0	-11.29	2.04	9.92	0.67	1.17	1.11	1.78	1.51
2DH5	2402.0	-9.97	2.00	9.92	1.95	1.57	1.11	3.06	2.02
2DH5	2441.0	-10.19	2.05	9.92	1.78	1.51	1.11	2.89	1.95
2DH5	2480.0	-10.42	2.04	9.92	1.54	1.43	1.11	2.65	1.84
3DH5	2402.0	-9.98	2.00	9.92	1.94	1.56	1.11	3.05	2.02
3DH5	2441.0	-10.18	2.05	9.92	1.79	1.51	1.11	2.90	1.95
3DH5	2480.0	-10.42	2.04	9.92	1.54	1.43	1.11	2.65	1.84

Sample Calculation:

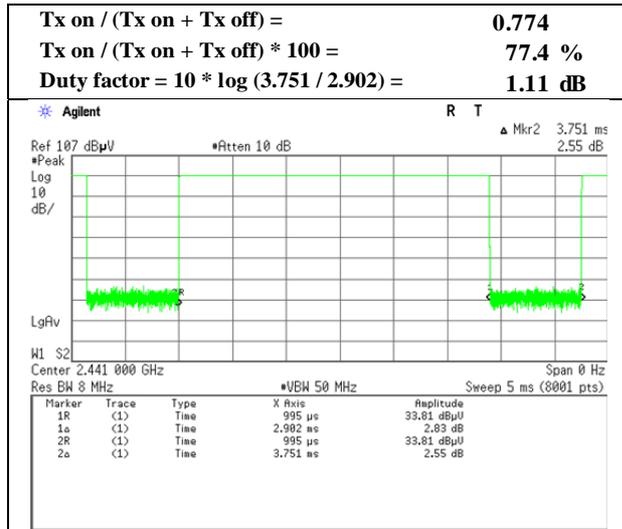
Result (Time average) = Reading + Cable Loss (including the cable(s) customer supplied) + Attenuator Loss

Result (Burst power average) = Frame power + Duty factor

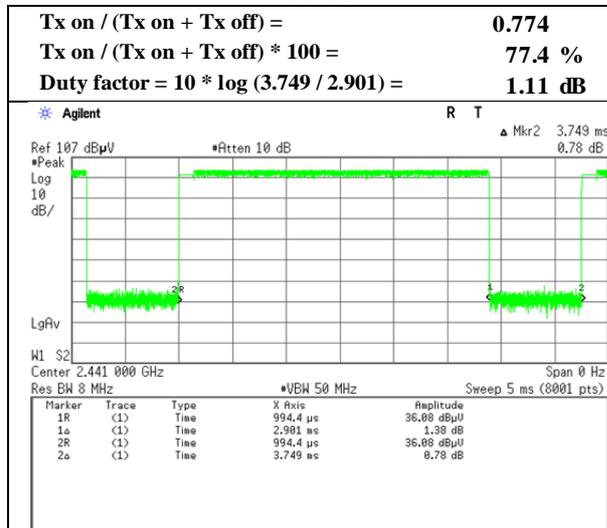
Burst Rate Confirmation

Test place	Shonan EMC Lab. No.5 Shielded Room
Report No.	11306371S-A-R1
Date	July 2, 2016
Temperature / Humidity	25 deg. C / 51 % RH
Engineer	Hiroyuki Morikawa
Mode	Tx, Hopping Off

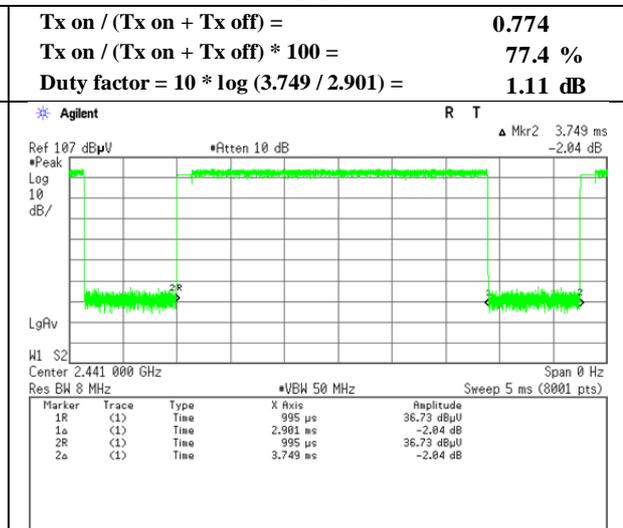
DH5



2DH5



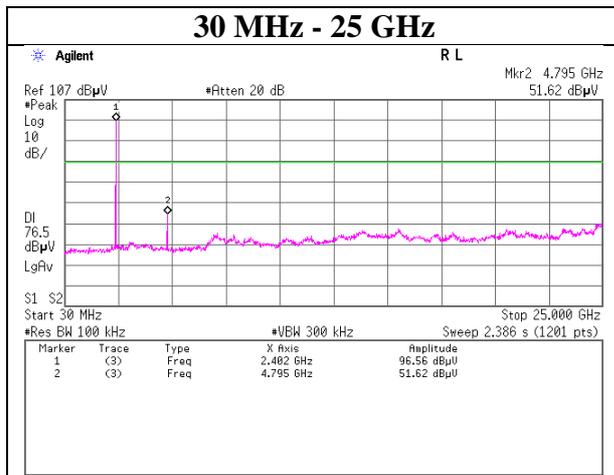
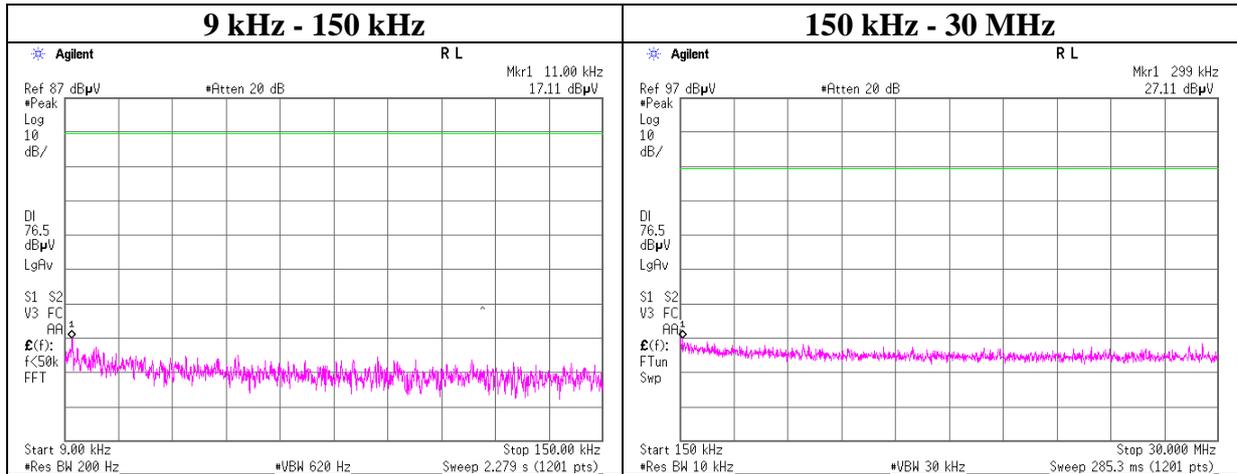
3DH5



Conducted Spurious Emission

Test place	Shonan EMC Lab. No.5 Shielded Room
Report No.	11306371S-A-R1
Date	July 2, 2016
Temperature / Humidity	25 deg. C / 51 % RH
Engineer	Hiroyuki Morikawa
Mode	Tx, Hopping Off, DH5

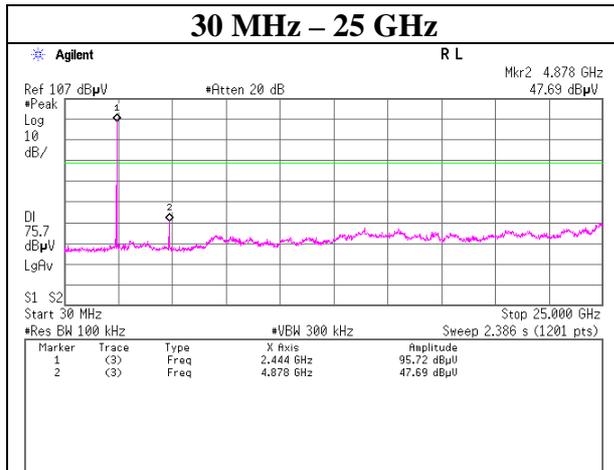
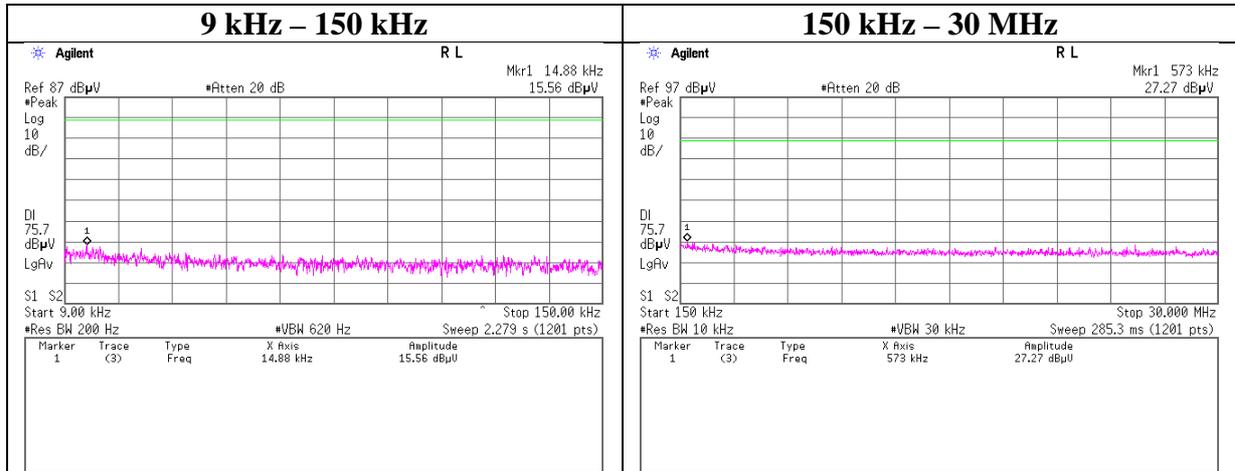
2402 MHz



Conducted Spurious Emission

Test place	Shonan EMC Lab. No.5 Shielded Room
Report No.	11306371S-A-R1
Date	July 2, 2016
Temperature / Humidity	25 deg. C / 51 % RH
Engineer	Hiroyuki Morikawa
Mode	Tx, Hopping Off, DH5

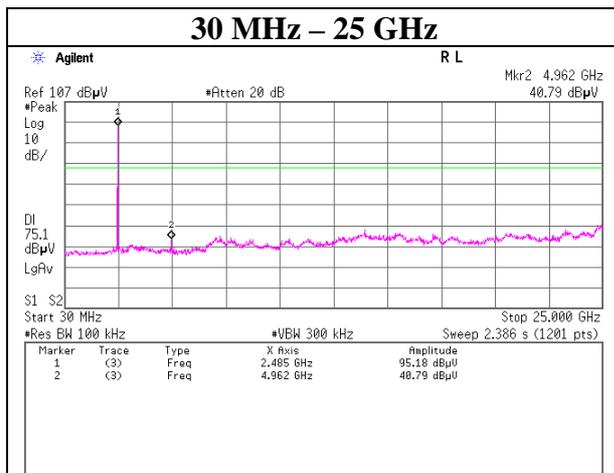
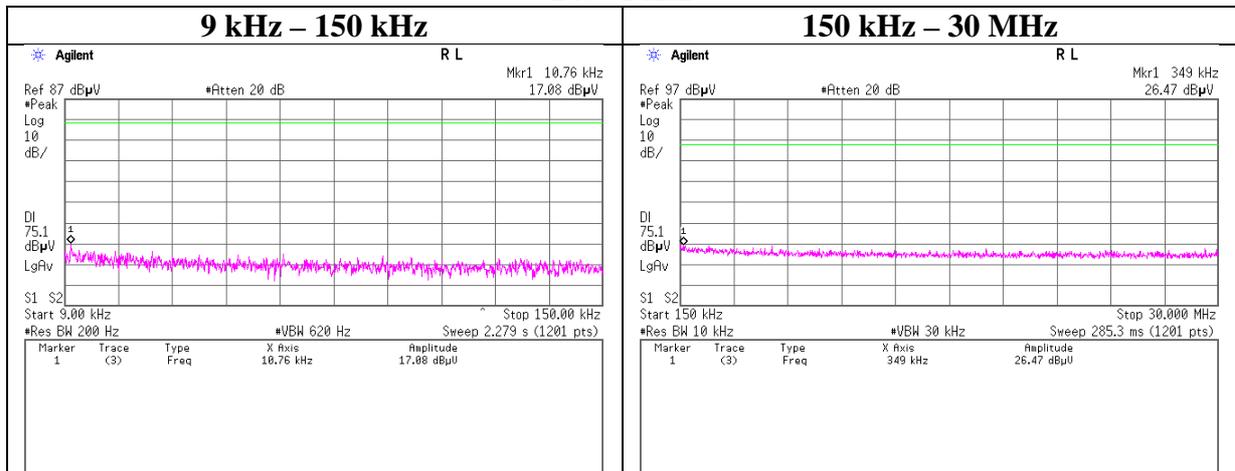
2441 MHz



Conducted Spurious Emission

Test place	Shonan EMC Lab. No.5 Shielded Room
Report No.	11306371S-A-R1
Date	July 2, 2016
Temperature / Humidity	25 deg. C / 51 % RH
Engineer	Hiroyuki Morikawa
Mode	Tx, Hopping Off, DH5

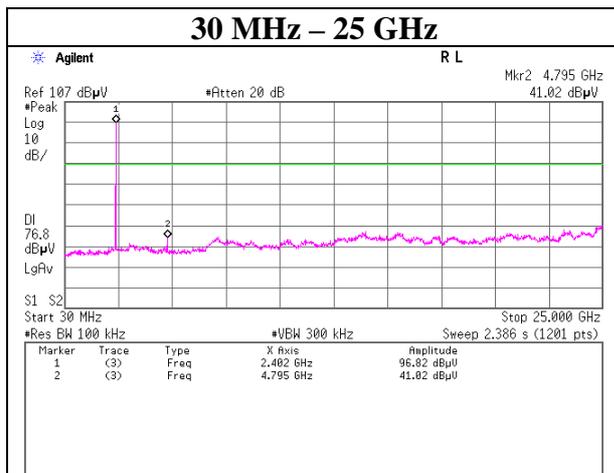
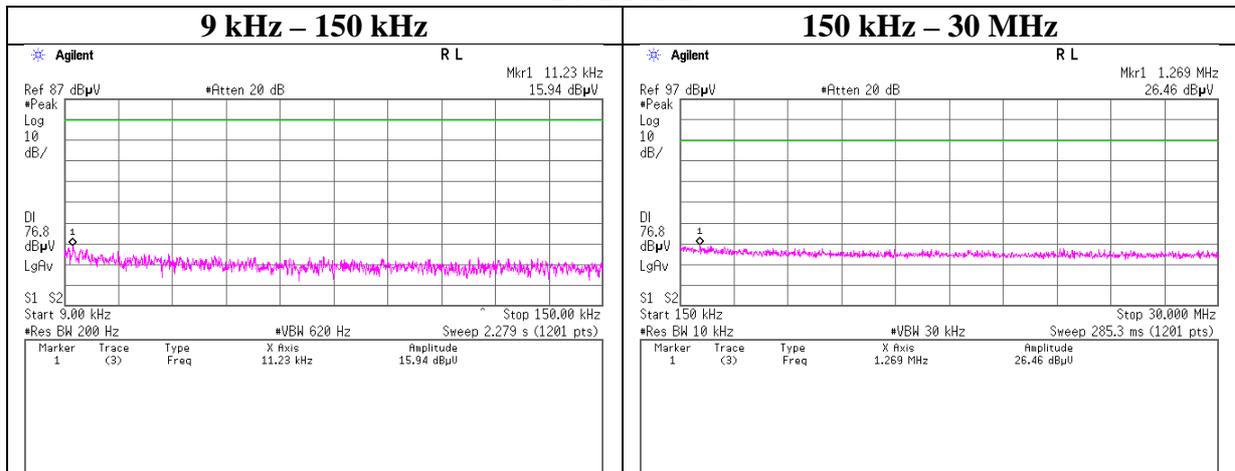
2480 MHz



Conducted Spurious Emission

Test place	Shonan EMC Lab. No.5 Shielded Room
Report No.	11306371S-A-R1
Date	July 2, 2016
Temperature / Humidity	25 deg. C / 51 % RH
Engineer	Hiroyuki Morikawa
Mode	Tx, Hopping Off, 3DH5

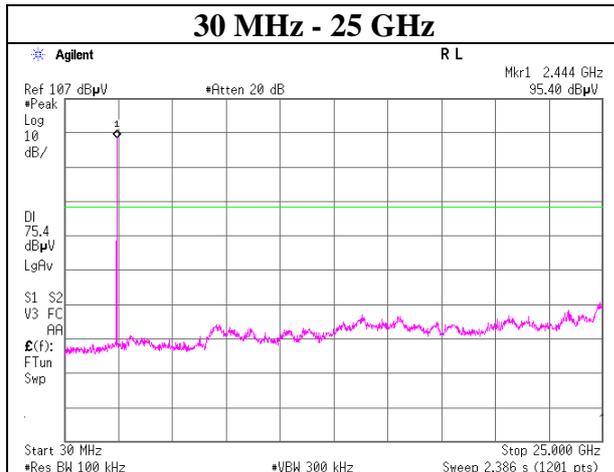
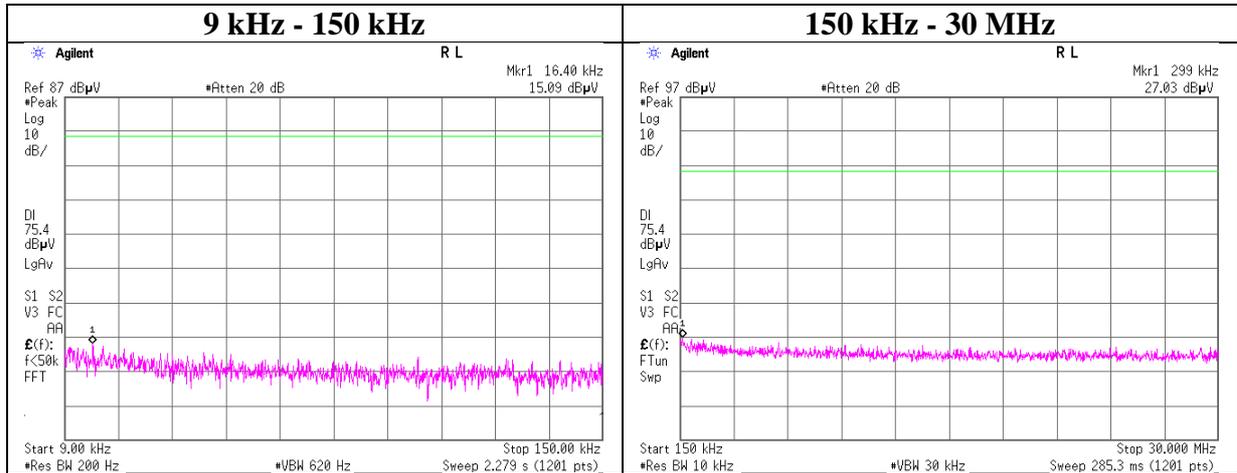
2402 MHz



Conducted Spurious Emission

Test place	Shonan EMC Lab. No.5 Shielded Room
Report No.	11306371S-A-R1
Date	July 2, 2016
Temperature / Humidity	25 deg. C / 51 % RH
Engineer	Hiroyuki Morikawa
Mode	Tx, Hopping Off, 3DH5

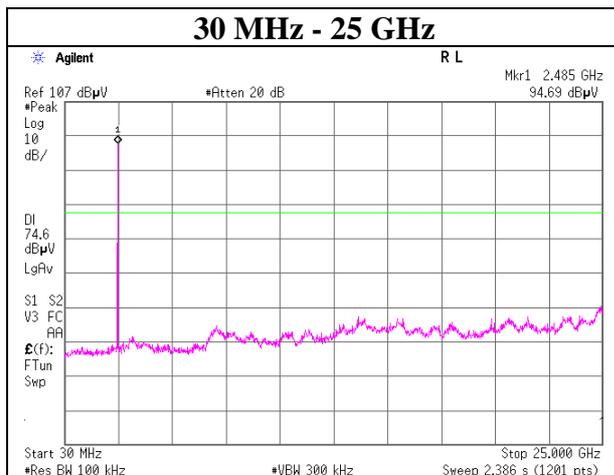
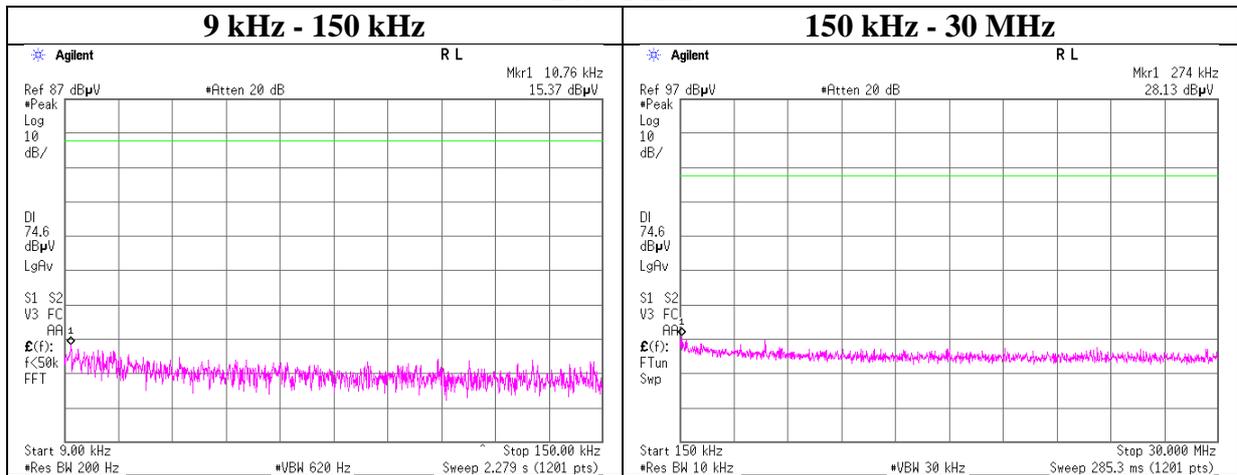
2441 MHz



Conducted Spurious Emission

Test place	Shonan EMC Lab. No.5 Shielded Room
Report No.	11306371S-A-R1
Date	July 2, 2016
Temperature / Humidity	25 deg. C / 51 % RH
Engineer	Hiroyuki Morikawa
Mode	Tx, Hopping Off, 3DH5

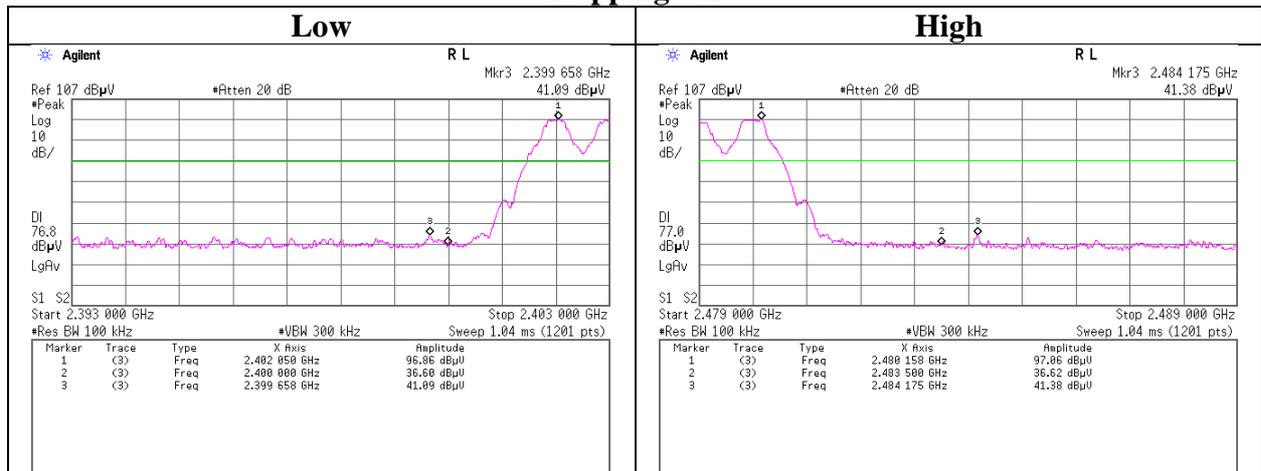
2480 MHz



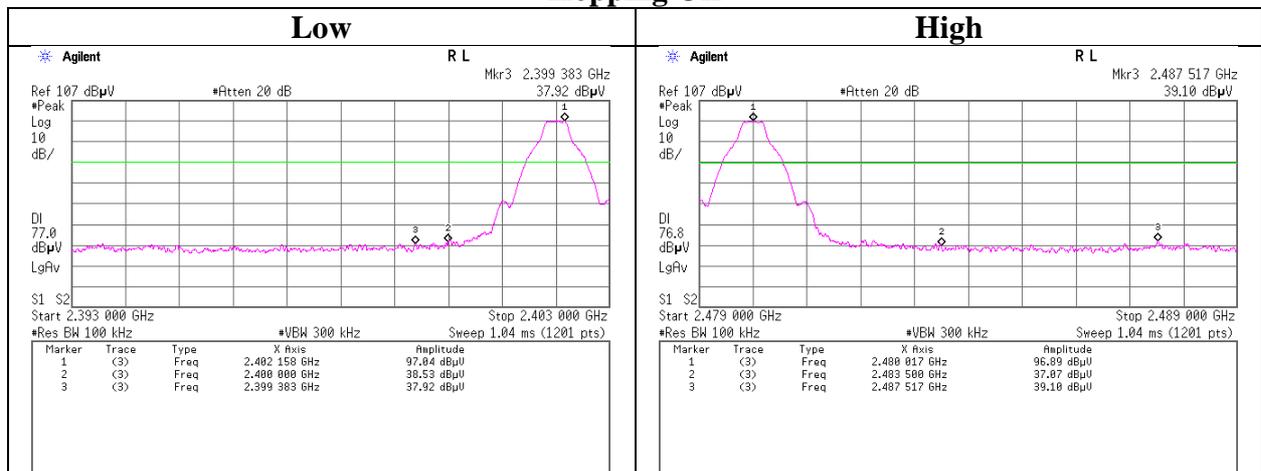
Conducted Emission Band Edge compliance

Test place	Shonan EMC Lab. No.5 Shielded Room
Report No.	11306371S-A-R1
Date	July 2, 2016
Temperature / Humidity	25 deg. C / 51 % RH
Engineer	Hiroyuki Morikawa
Mode	Tx DH5

Hopping On



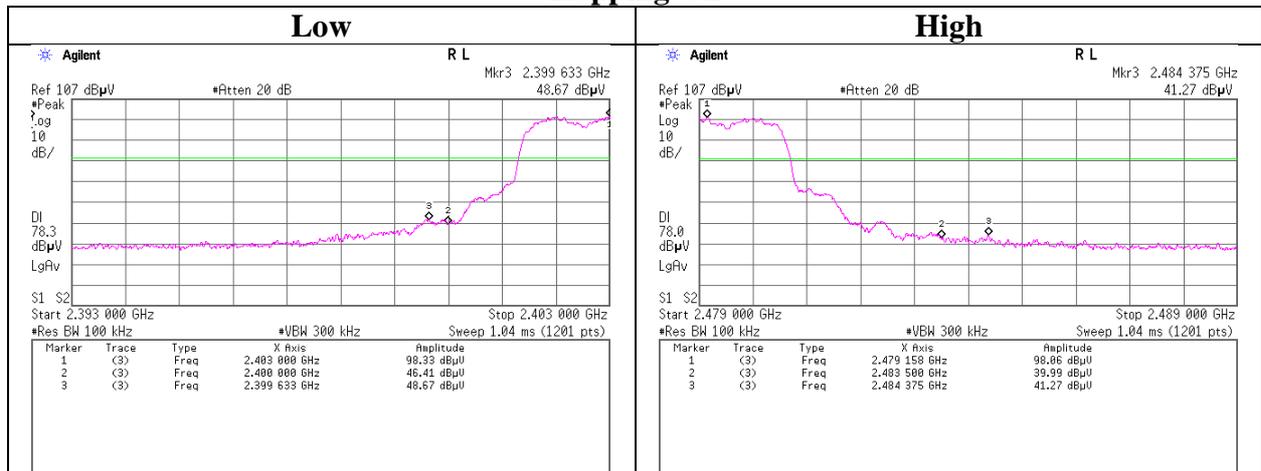
Hopping Off



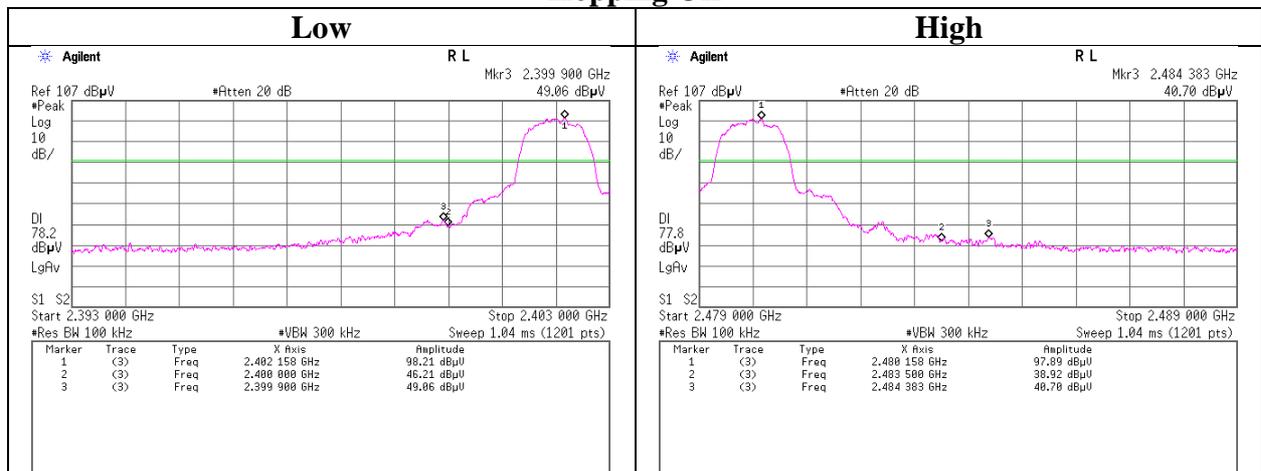
Conducted Emission Band Edge compliance

Test place	Shonan EMC Lab. No.5 Shielded Room
Report No.	11306371S-A-R1
Date	July 2, 2016
Temperature / Humidity	25 deg. C / 51 % RH
Engineer	Hiroyuki Morikawa
Mode	Tx 3DH5

Hopping On



Hopping Off

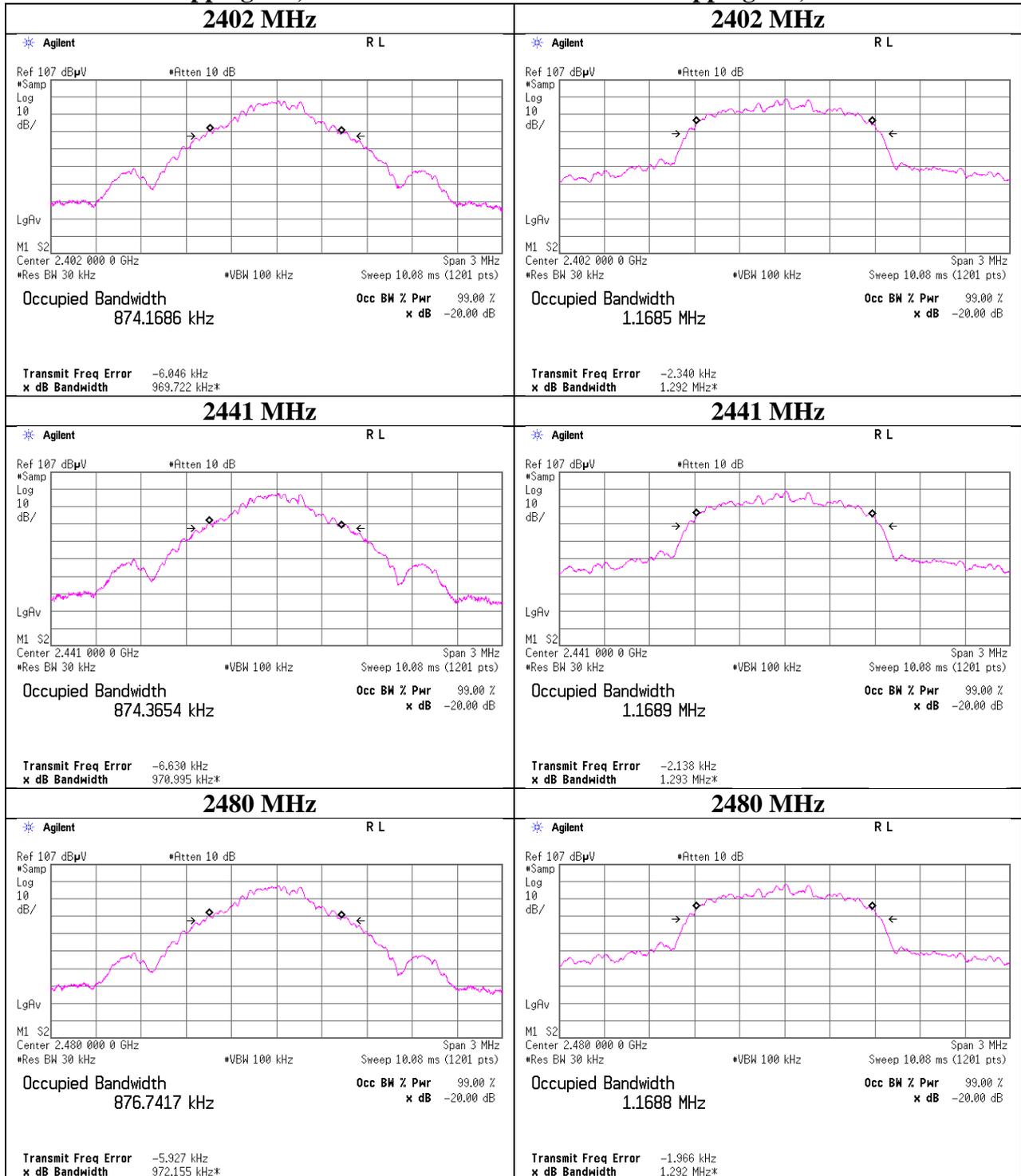


99% Occupied Bandwidth

Test place	Shonan EMC Lab. No.5 Shielded Room
Report No.	11306371S-A-R1
Date	July 2, 2016
Temperature / Humidity	25 deg. C / 51 % RH
Engineer	Hiroyuki Morikawa
Mode	Tx Hopping Off

Hopping Off, DH5

Hopping Off, 3DH5



UL Japan, Inc.

Shonan EMC Lab.

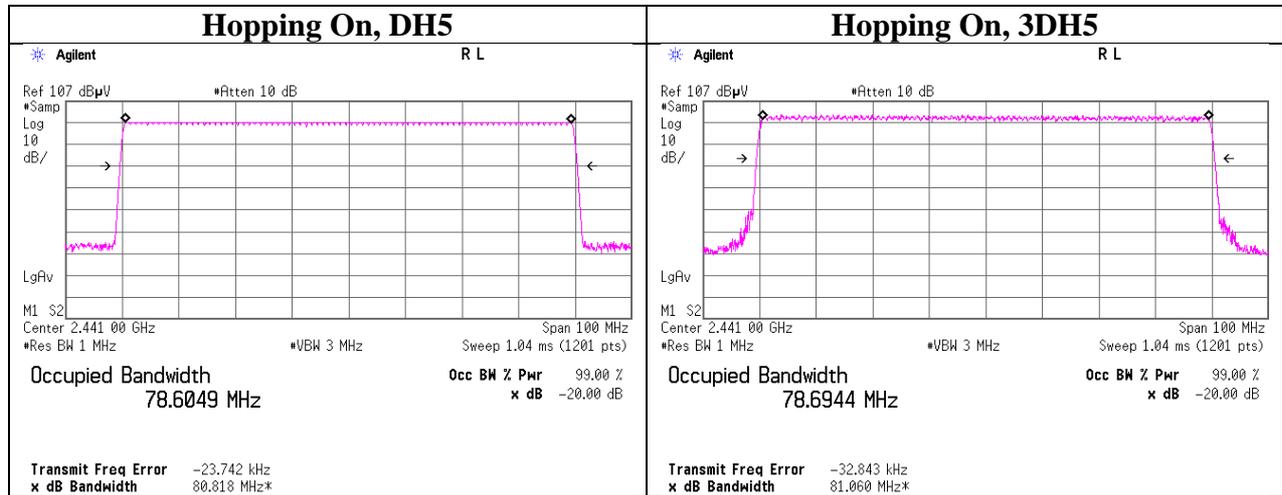
1-22-3 Megumigaoka, Hiratsuka-shi, Kanagawa-ken, 259-1220 JAPAN

Telephone : +81 463 50 6400

Facsimile : +81 463 50 6401

99% Occupied Bandwidth

Test place	Shonan EMC Lab. No.5 Shielded Room
Report No.	11306371S-A-R1
Date	July 2, 2016
Temperature / Humidity	25 deg. C / 51 % RH
Engineer	Hiroyuki Morikawa
Mode	Tx Hopping On



APPENDIX 2: Test instruments

Test equipment

Control No.	Instrument	Manufacturer	Model No	Serial No	Test Item	Calibration Date * Interval(month)
KSA-08	Spectrum Analyzer	Agilent	E4446A	MY4618052 5	AT	2016/03/28 * 12
SAT10-10	Attenuator	Weinschel Corp.	54A-10	37584	AT	2016/04/18 * 12
SCC-G31	Coaxial Cable	Junkosha	MWX241-0100 0KMSKMS	OCT-08-13- 046	AT	2016/04/18 * 12
SPM-07	Power Meter	Agilent	8990B	MY5100272	AT	2016/04/04 * 12
SPSS-04	Power sensor	Agilent	N1923A	MY5326009	AT	2016/04/04 * 12
STM-G4	Terminator	Weinschel	M1459A	U6592	AT	2015/07/14 * 12
SOS-09	Humidity Indicator	A&D	AD-5681	4061484	AT	2015/12/07 * 12

The expiration date of the calibration is the end of the expired month.

All equipment is calibrated with valid calibrations. Each measurement data is traceable to the national or international standards.

As for some calibrations performed after the tested dates, those test equipment have been controlled by means of an unbroken chains of calibrations.

Test Item: AT: Antenna Terminal Conducted test